IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re divisional patent application of 09/690,875 filed on October 18, 2000

Cohen et al.

Serial No.: Not Yet Assigned Group Art Unit: Not Yet Assigned

Filing Date: Concurrently Herewith Examiner: Unknown

For: DOUBLE-GATE FET WITH PLANARIZED SURFACES AND SELF ALIGNED

SILICIDES

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Under the provisions of 37 CFR §1.97 through §1.99 and pursuant to applicant's duty of disclosure under 37 CFR §1.56, applicant respectfully brings the following documents listed on the attached form PTO-1449, to the attention of the Examiner in charge of the above-identified application. All of these references were either cited or submitted in parent Application No. 09/690,875 and thus copies of these references are not provided in accordance with 37 C.F.R. §1.98(d).

This citation does not constitute an admission that the references are relevant or material to the claims. They are only cited as constituting related art of which the applicant is aware.

It is respectfully requested that the listed references be considered by the Examiner and formally made of record in this application.

YOR920000173US2

Please charge any deficiencies in fees and credit any overpayment of fees to Attorney's Deposit Account No. 50-0510.

Respectfully submitted,

Frederick W. Gibb, III Registration No. 37,629

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F rm PTO-A820 (also form PTO-1449)

P09C/REV03

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

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Cohen et al.		
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